

#### Feature

- Precision MEMS process
- High performance, shielded, Micro-cavity structure
- Silicon substrate,  $50\Omega$  CPW output
- •Au wire bonding, for MCM applications

### **Environmental Specifications**

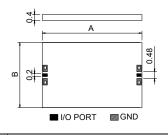
Operating Temperature	-55°C~+85°C	
Storage Temperature	-55℃~+125℃	
Max. Input Power	35dBm	

## Electrical Specifications(T<sub>A</sub>=+25°C)

Parameter	Min.	Тур.	Max.	Unit
Center Freq. (f <sub>0</sub> )	-	15.55	-	GHz
Pass Band	15.25	-	15.85	GHz
Ripple in Pass band	-	-	1	dB
Insertion Loss @ fo	-	-	3.5	dB
Return Loss	12	-	-	dB
	≥30@14.8&16.4GHz		Z	dB
Out of band	≥40@14.7&16.6GHz			dB
Attenuation	≥55@DC~14GHz			dB
	≥50@18~20GHz			dB
Group Delay Variation	≤1@15.25~15.85 GHz			ns
Linear Phase	≤±5@15.25~15.85 GHz			0

S2P file name: SiMS15R55\_R6-6S3.s2p

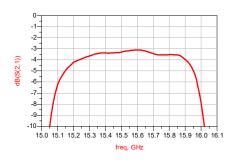
#### **Outline Drawing**

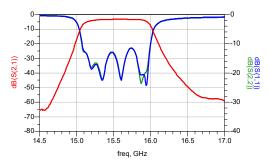


Symbol		Value (mm)		
	Symbol	Min.	Nominal	Max.
ſ	А	7.4	-	7.5
	В	3.4	-	3.5

## **Typical Test Curves**

Insertion	Loss V	S Freauency	(T <sub>A</sub> =25°C)



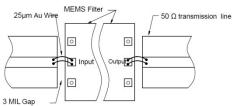


Insertion Loss & Return Loss VS Frequency (T<sub>A</sub>=25°C)

Broadband Insertion Loss VS Frequency (T<sub>A</sub>=25°C)



## **Recommended Assembly Diagrams**



# **Application Notes:**

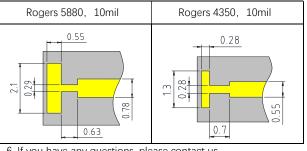
1. The chip is back-metalized and can be die mounted with AuSn eutectic performs or with electrically conductive epoxy (for example ME8456).

2. The die should be assembled on carriers like Kovar or Mu-Cu which have same Coefficient of thermal expansion. (2.9ppm/°C) with Silicon, thickness 0.2mm max.

3. Handle the chips in a clean environment. DO NOT attempt to clean the chip using liquid cleaning systems.

4. Handle the chip along the edges with a vacuum collet or with a sharp pair of bent tweezers.

5. Recommended to use T structure as below for bonding.



6. If you have any questions, please contact us.